

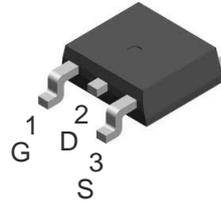
**650V / 4A**  
**N-Channel Enhancement Mode MOSFET**

650V,  $R_{DS(ON)}=2.8\Omega @ V_{GS}=10V, I_D=2A$

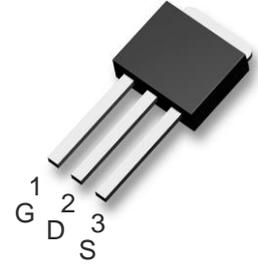
### Features

- Low On-State Resistance
- Fast Switching
- Low Gate Charge & Low  $C_{RSS}$
- Fully Characterized Avalanche Voltage and Current
- Specially Designed for AC Adapter, Battery Charger and SMPS
- In compliance with EU RoHs 2002/95/EC Directives

TO-252



TO-251

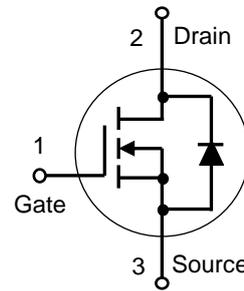


### Mechanical Information

- Case: TO-252 / TO-251 Molded Plastic
- Terminals : Solderable per MIL-STD-750, Method 2026

### Marking & Ordering Information

TYPE	MARKING	PACKAGE	PACKING
HY4N65D	4N65D	TO-252	2500PCS/REEL
HY4N65M	4N65M	TO-251	80PCS/TUBE



### Absolute Maximum Ratings ( $T_c=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	HY4N65D	HY4N65M	Units
Drain-Source Voltage	$V_{DS}$	650		V
Gate-Source Voltage	$V_{GS}$	$\pm 30$		V
Continuous Drain Current	$I_D$	4	4	A
Pulsed Drain Current <sup>1)</sup>	$I_{DM}$	16	16	A
Maximum Power Dissipation	$P_D$	56.8	48	W
Derating Factor		0.46	0.39	
Avalanche Energy with Single Pulse	$E_{AS}$	180		mJ
$I_{AS}=4A, V_{DD}=150V, L=22.5mH$				
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to +150		$^\circ\text{C}$

Note : 1. Maximum DC current limited by the package

### Thermal Characteristics

Parameter	Symbol	HY4N65D	HY4N65M	Units
Junction-to-Case Thermal Resistance	$R_{\theta JC}$	2.2	2.6	$^\circ\text{C/W}$
Junction-to-Air Thermal Resistance	$R_{\theta JA}$	50	110	$^\circ\text{C/W}$

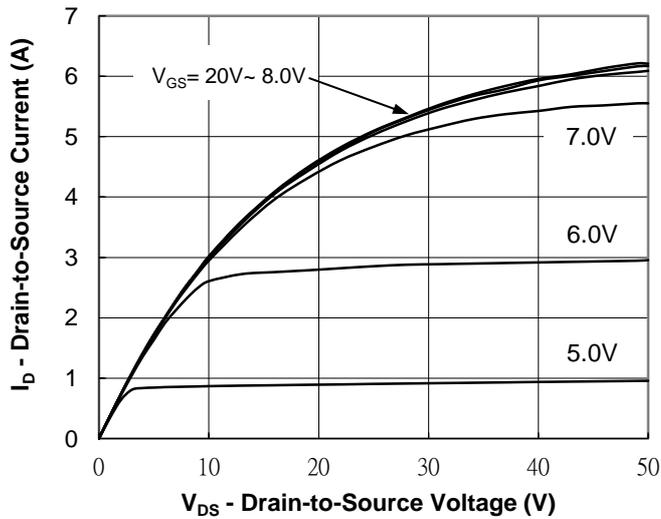
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**Electrical Characteristics (  $T_c=25^\circ\text{C}$  , Unless otherwise noted )**

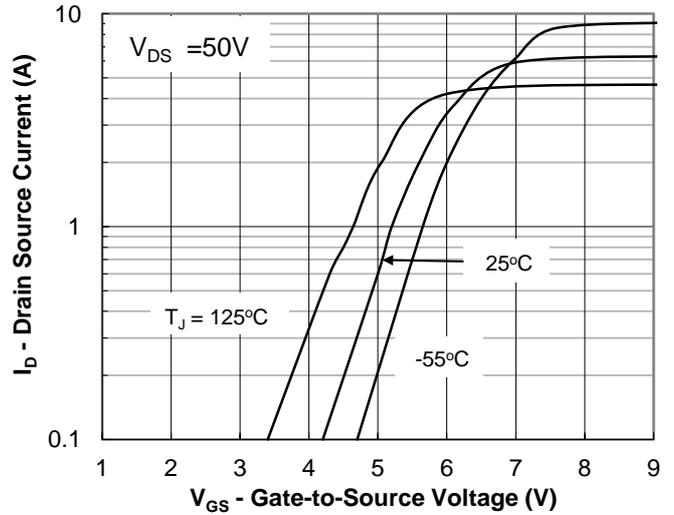
Paramter	Symbol	Test Condition	Min.	Typ.	Max.	Units
<b>Static</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0V \cdot I_D=250\mu A$	650	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS} \cdot I_D=250\mu A$	2.0	-	4.0	V
Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS}=10V \cdot I_D=2A$	-	2.5	2.8	$\Omega$
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=650V \cdot V_{GS}=0V$	-	-	10	$\mu A$
Gate Body Leakage Current	$I_{GSS}$	$V_{GS}=\pm 30V \cdot V_{DS}=0V$	-	-	$\pm 100$	nA
<b>Dynamic</b>						
Total Gate Charge	Qg	$V_{DS}=520V \cdot I_D=4A$ $V_{GS}=10V$	-	16.2	20	nC
Gate-Source Charge	Qgs		-	3.2	-	
Gate-Drain Charge	Qgd		-	5.6	-	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD}=325V \cdot I_D=4A$ $V_{GS}=10V \cdot R_G=25\Omega$	-	16.8	22	ns
Turn-On Rise Time	$t_r$		-	36	46	
Turn-Off Delay Time	$t_{d(off)}$		-	21.8	32	
Turn-Off Fall Time	$t_f$		-	19.2	28	
Input Capacitance	$C_{iss}$	$V_{DS}=25V \cdot V_{GS}=0V$ $f=1.0M_{HZ}$	-	480	-	pF
Output Capacitance	$C_{oss}$		-	65	-	
Reverse Transfer Capacitance	$C_{riss}$		-	1.3	-	
<b>Source-Drain Diode</b>						
Max. Diode Forwad Voltage	$I_S$	-	-	-	4.0	A
Max. Pulsed Source Current	$I_{SM}$	-	-	-	16	A
Diode Forward Voltage	$V_{SD}$	$I_S=4A \cdot V_{GS}=0V$	-	-	1.4	V
Reverse Recovery Time	$t_{rr}$	$V_{GS}=0V \cdot I_S=4A$ $di/dt=100A/\mu s$	-	210	-	ns
Reverse Recovery Charge	$Q_{rr}$		-	0.8	-	$\mu C$

**NOTE** : Pulse Test : Pulse Width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$

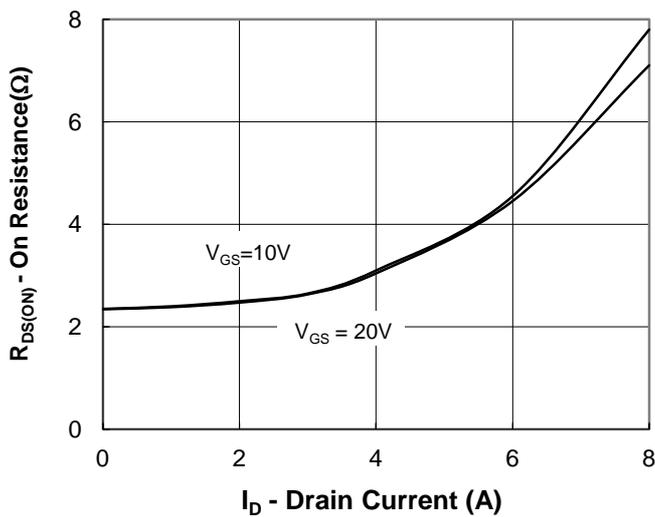
### Typical Characteristics Curves ( $T_C=25^\circ\text{C}$ , unless otherwise noted)



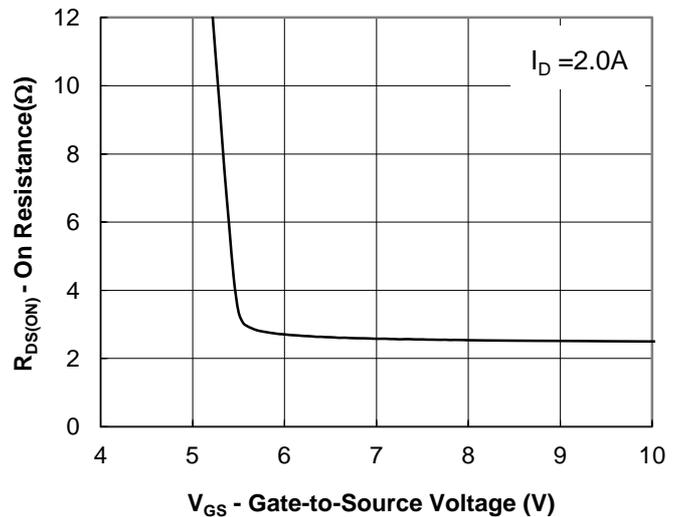
**Fig.1 Output Characteristic**



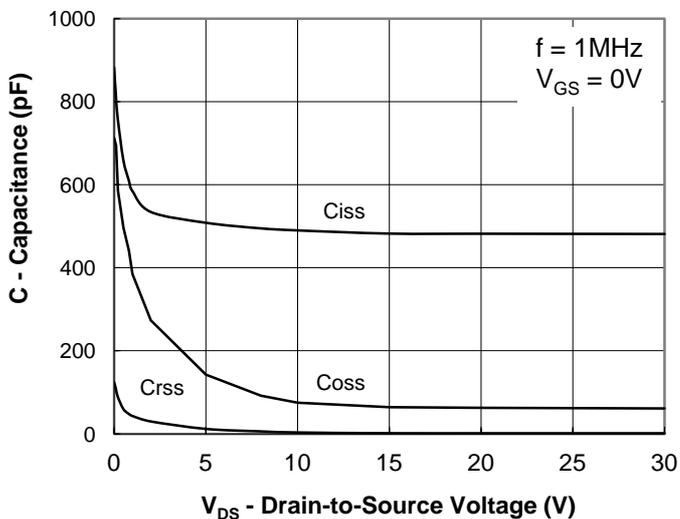
**Fig.2 Transfer Characteristic**



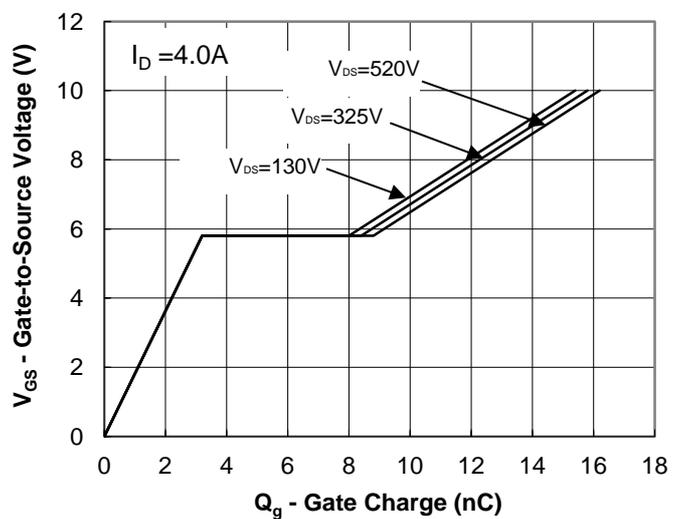
**Fig.3 On-Resistance vs Drain Current**



**Fig.4 On-Resistance vs Gate to Source Voltage**



**Fig.5 Capacitance Characteristic**



**Fig.6 Gate Charge Characteristic**

### Typical Characteristics Curves ( $T_C=25^\circ\text{C}$ , unless otherwise noted)

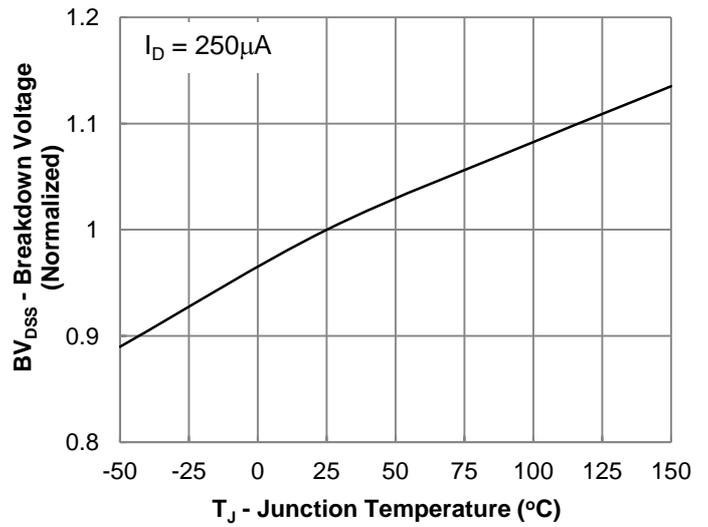
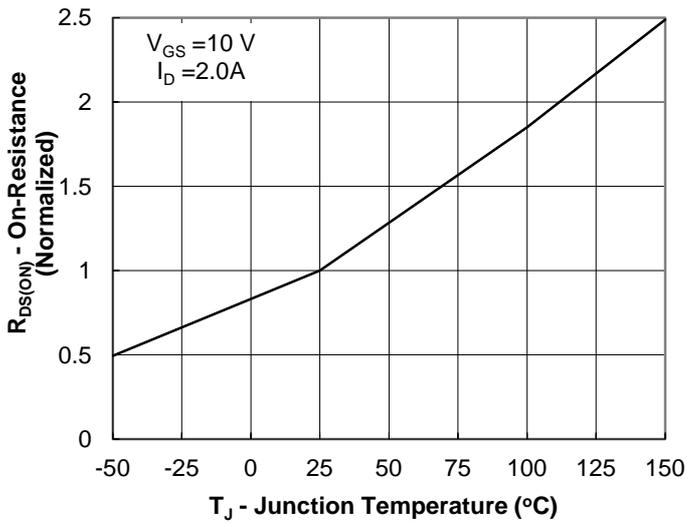


Fig.7 On-Resistance vs Junction Temperature

Fig.8 Breakdown Voltage vs Junction Temperature

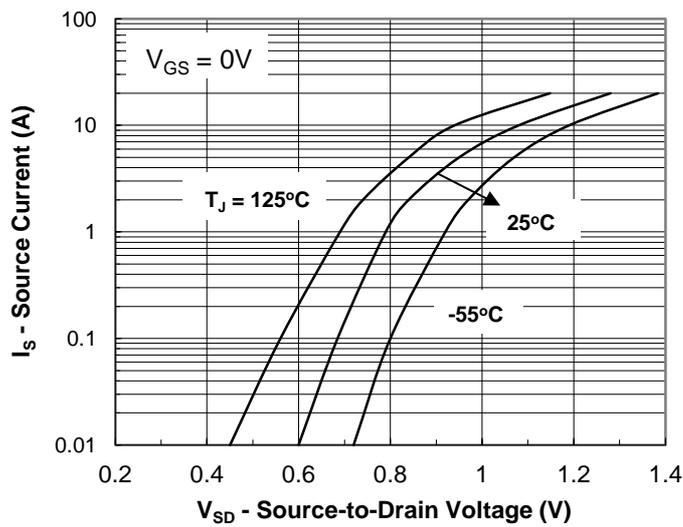


Fig.9 Body Diode Forward Voltage Characteristic